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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

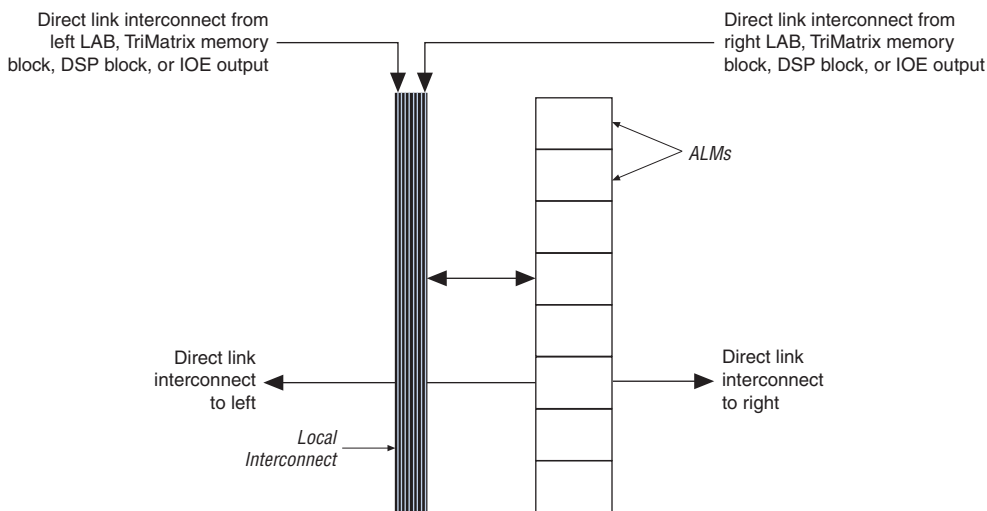
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	780
Number of Logic Elements/Cells	15600
Total RAM Bits	419328
Number of I/O	366
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2s15f672i4

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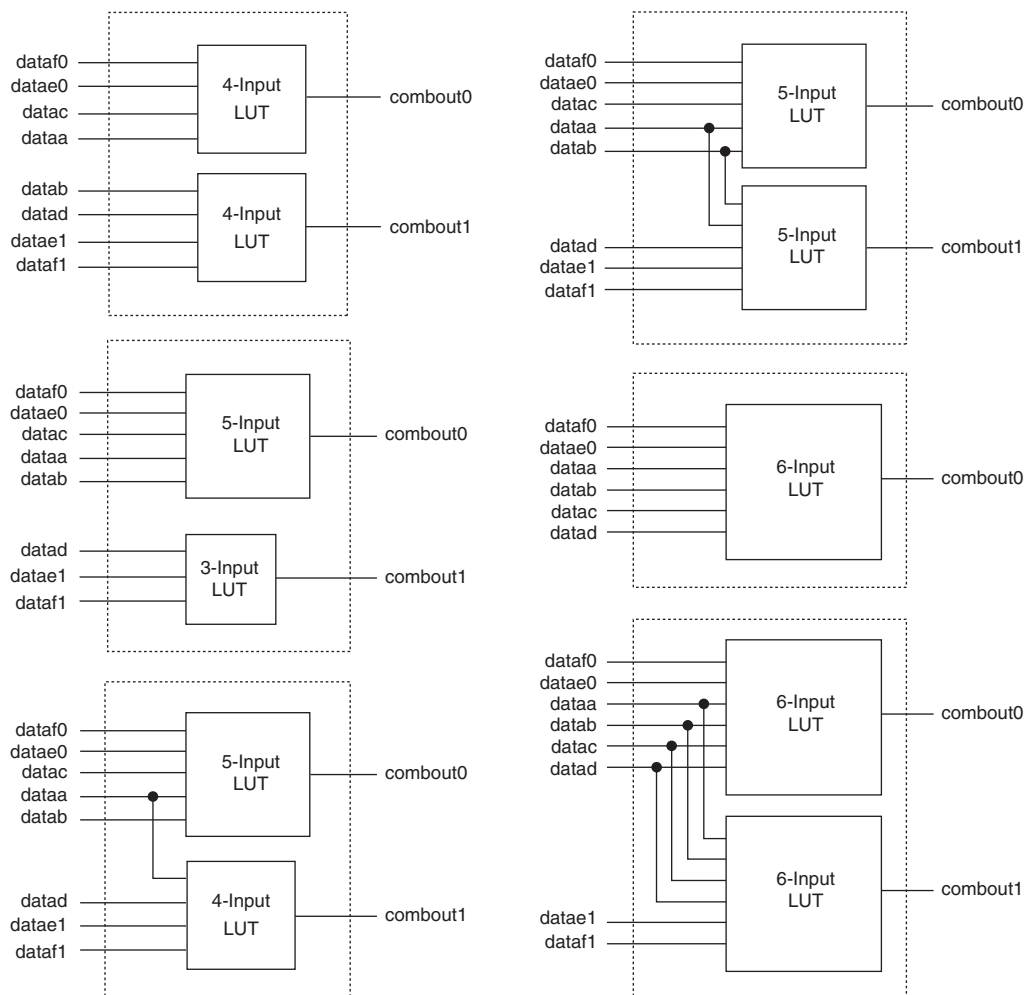
Figure 2–3. Direct Link Connection

LAB Control Signals

Each LAB contains dedicated logic for driving control signals to its ALMs. The control signals include three clocks, three clock enables, two asynchronous clears, synchronous clear, asynchronous preset/load, and synchronous load control signals. This gives a maximum of 11 control signals at a time. Although synchronous load and clear signals are generally used when implementing counters, they can also be used with other functions.

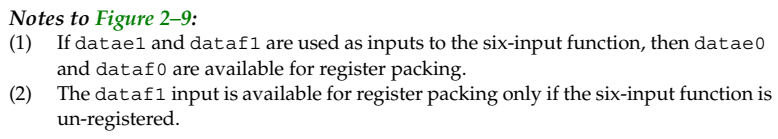
Each LAB can use three clocks and three clock enable signals. However, there can only be up to two unique clocks per LAB, as shown in the LAB control signal generation circuit in [Figure 2–4](#). Each LAB's clock and clock enable signals are linked. For example, any ALM in a particular LAB using the `labclk1` signal also uses `labck1ena1`. If the LAB uses both the rising and falling edges of a clock, it also uses two LAB-wide clock signals. De-asserting the clock enable signal turns off the corresponding LAB-wide clock.

Each LAB can use two asynchronous clear signals and an asynchronous load/preset signal. By default, the Quartus II software uses a NOT gate push-back technique to achieve preset. If you disable the NOT gate push-up option or assign a given register to power up high using the Quartus II software, the preset is achieved using the asynchronous load

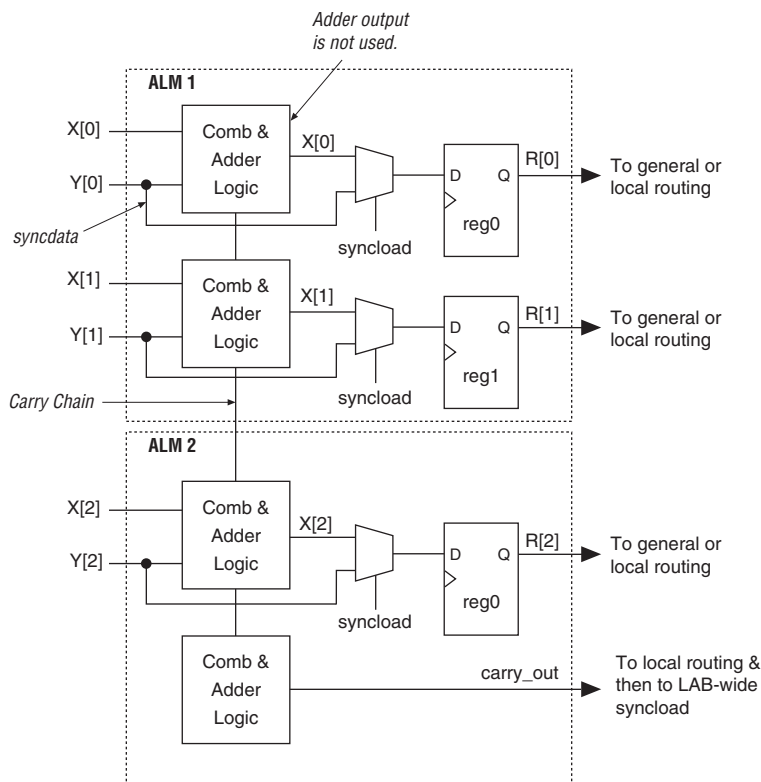
Figure 2–7. ALM in Normal Mode *Note (1)***Note to Figure 2–7:**

- (1) Combinations of functions with fewer inputs than those shown are also supported. For example, combinations of functions with the following number of inputs are supported: 4 and 3, 3 and 3, 3 and 2, 5 and 2, etc.

The normal mode provides complete backward compatibility with four-input LUT architectures. Two independent functions of four inputs or less can be implemented in one Stratix II ALM. In addition, a five-input function and an independent three-input function can be implemented without sharing inputs.



The extended LUT mode is used to implement a specific set of seven-input functions. The set must be a 2-to-1 multiplexer fed by two arbitrary five-input functions sharing four inputs. [Figure 2–10](#) shows the template of supported seven-input functions utilizing extended LUT mode. In this mode, if the seven-input function is unregistered, the unused eighth input is available for register packing.

Figure 2–12. Conditional Operation Example

The arithmetic mode also offers clock enable, counter enable, synchronous up/down control, add/subtract control, synchronous clear, synchronous load. The LAB local interconnect data inputs generate the clock enable, counter enable, synchronous up/down and add/subtract control signals. These control signals are good candidates for the inputs that are shared between the four LUTs in the ALM. The synchronous clear and synchronous load options are LAB-wide signals that affect all registers in the LAB. The Quartus II software automatically places any registers that are not used by the counter into other LABs.

Carry Chain

The carry chain provides a fast carry function between the dedicated adders in arithmetic or shared arithmetic mode. Carry chains can begin in either the first ALM or the fifth ALM in an LAB. The final carry-out signal is routed to an ALM, where it is fed to local, row, or column interconnects.

Figure 2–26. M-RAM Row Unit Interface to Interconnect

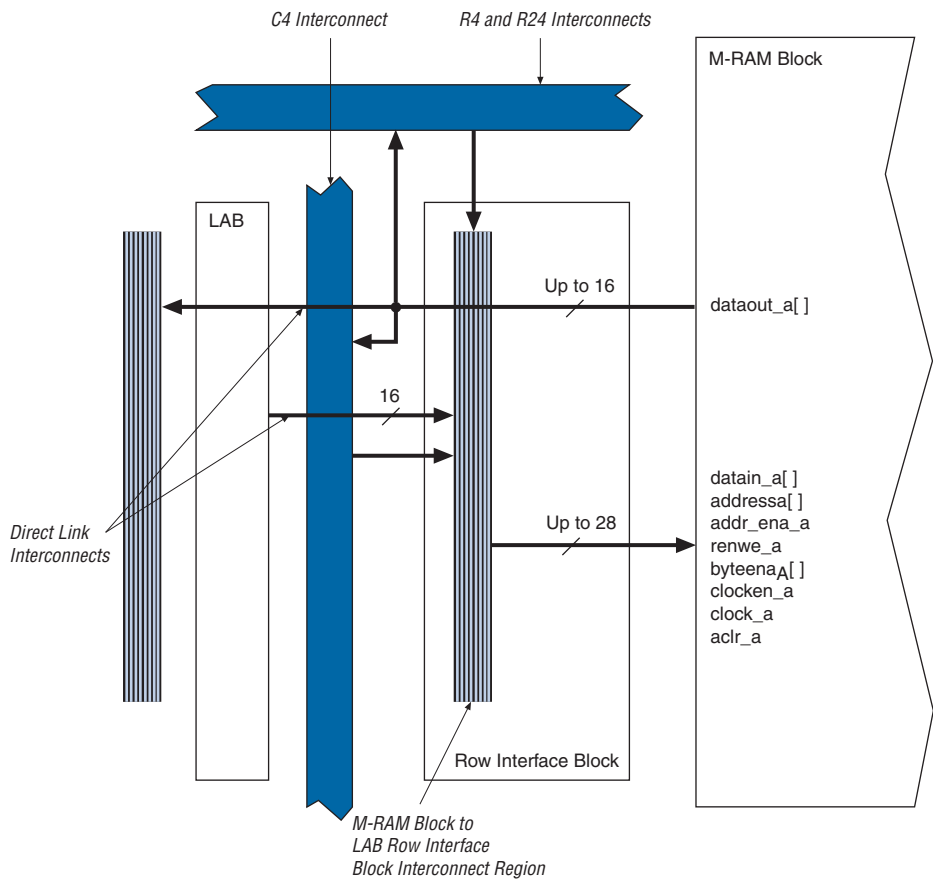


Table 2–4 shows the input and output data signal connections along with the address and control signal input connections to the row unit interfaces (L0 to L5 and R0 to R5).

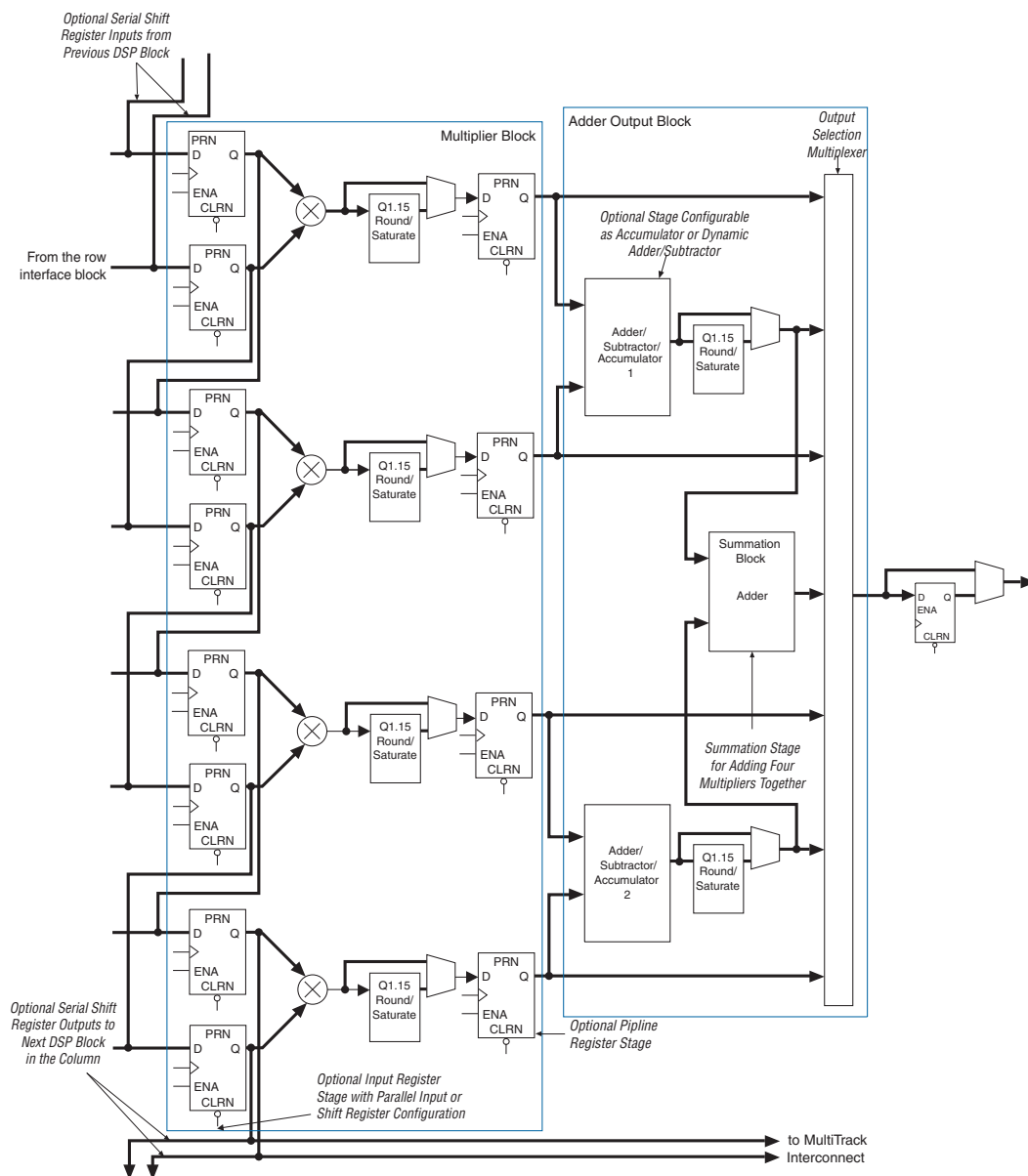
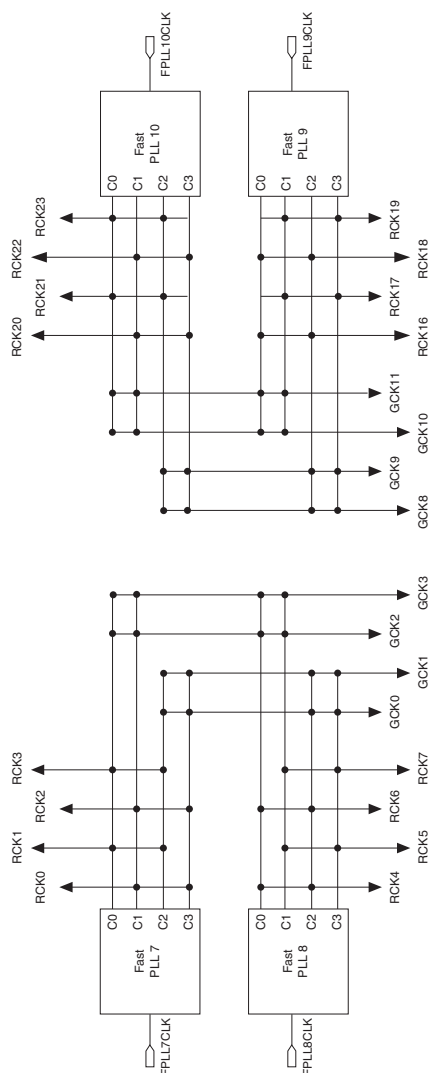
Figure 2–28. DSP Block Diagram for 18 × 18-Bit Configuration

Figure 2–42. Global & Regional Clock Connections from Corner Clock Pins & Fast PLL Outputs *Note (1)*

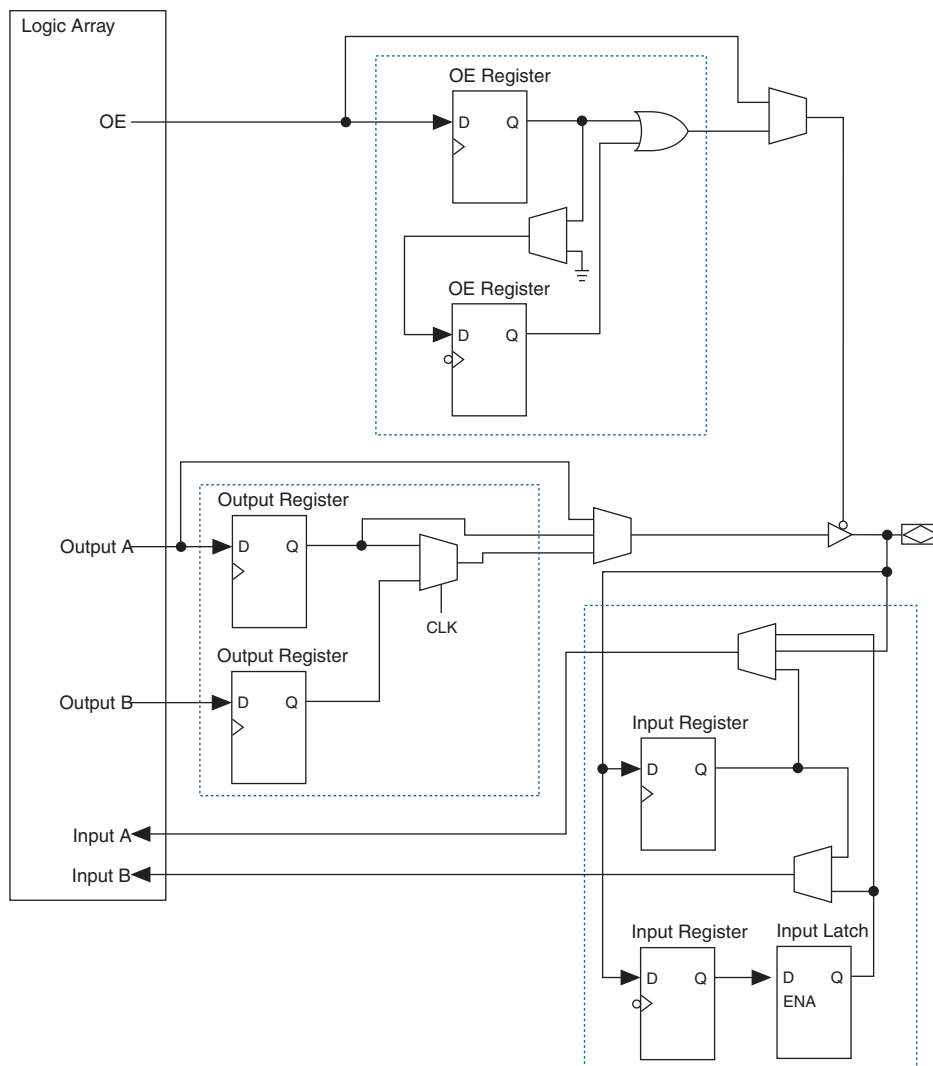


Note to Figure 2–42:

- (1) The corner fast PLLs can also be driven through the global or regional clock networks. The global or regional clock input can be driven by an output from another PLL, a pin-driven dedicated global or regional clock, or through a clock control block, provided the clock control block is fed by an output from another PLL or a pin-driven dedicated global or regional clock. An internally generated global signal cannot drive the PLL.

Table 2–12. Global & Regional Clock Connections from Bottom Clock Pins & Enhanced PLL Outputs (Part 2 of 2)

Bottom Side Global & Regional Clock Network Connectivity	DLLCLK	CLK4	CLK5	CLK6	CLK7	RCLK8	RCLK9	RCLK10	RCLK11	RCLK12	RCLK13	RCLK14	RCLK15
GCLKDRV3					✓								
RCLKDRV0						✓				✓			
RCLKDRV1							✓				✓		
RCLKDRV2								✓				✓	
RCLKDRV3									✓				✓
RCLKDRV4						✓				✓			
RCLKDRV5							✓				✓		
RCLKDRV6								✓				✓	
RCLKDRV7									✓				✓
Enhanced PLL 6 outputs													
c0	✓	✓	✓			✓				✓			
c1	✓	✓	✓				✓				✓		
c2	✓			✓	✓			✓				✓	
c3	✓			✓	✓				✓				✓
c4	✓					✓		✓		✓		✓	
c5	✓						✓		✓		✓		✓
Enhanced PLL 12 outputs													
c0		✓	✓			✓				✓			
c1		✓	✓				✓				✓		
c2				✓	✓			✓				✓	
c3				✓	✓				✓				✓
c4						✓		✓		✓		✓	
c5							✓		✓		✓		✓

Figure 2–46. Stratix II IOE Structure

The IOEs are located in I/O blocks around the periphery of the Stratix II device. There are up to four IOEs per row I/O block and four IOEs per column I/O block. The row I/O blocks drive row, column, or direct link interconnects. The column I/O blocks drive column interconnects.

Figure 2–47 shows how a row I/O block connects to the logic array.

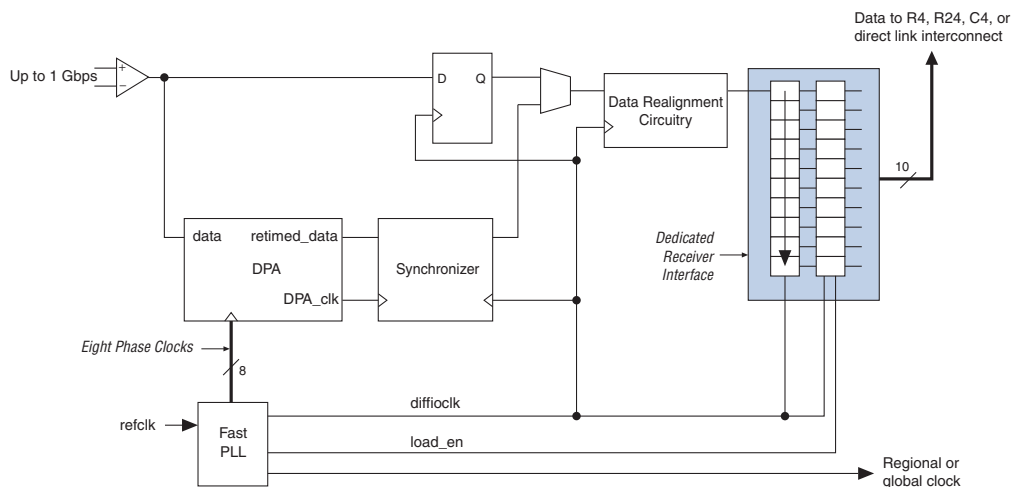
Figure 2–48 shows how a column I/O block connects to the logic array.

Table 2–17. On-Chip Termination Support by I/O Banks (Part 2 of 2)

On-Chip Termination Support	I/O Standard Support	Top & Bottom Banks	Left & Right Banks
Series termination with calibration	3.3-V LVTTTL	✓	
	3.3-V LVCMOS	✓	
	2.5-V LVTTTL	✓	
	2.5-V LVCMOS	✓	
	1.8-V LVTTTL	✓	
	1.8-V LVCMOS	✓	
	1.5-V LVTTTL	✓	
	1.5-V LVCMOS	✓	
	SSTL-2 Class I and II	✓	
	SSTL-18 Class I and II	✓	
	1.8-V HSTL Class I	✓	
	1.8-V HSTL Class II	✓	
	1.5-V HSTL Class I	✓	
	1.2-V HSTL	✓	
Parallel termination with calibration	SSTL-2 Class I and II	✓	
	SSTL-18 Class I and II	✓	
	1.8-V HSTL Class I	✓	
	1.8-V HSTL Class II	✓	
	1.5-V HSTL Class I and II	✓	
	1.2-V HSTL	✓	
Differential termination (1)	LVDS		✓
	HyperTransport technology		✓

Note to Table 2–17:

- (1) Clock pins CLK1, CLK3, CLK9, CLK11, and pins FPLL[7..10] CLK do not support differential on-chip termination. Clock pins CLK0, CLK2, CLK8, and CLK10 do support differential on-chip termination. Clock pins in the top and bottom banks (CLK[4..7, 12..15]) do not support differential on-chip termination.

Figure 2–59. Stratix II Receiver Channel

An external pin or global or regional clock can drive the fast PLLs, which can output up to three clocks: two multiplied high-speed clocks to drive the SERDES block and/or external pin, and a low-speed clock to drive the logic array. In addition, eight phase-shifted clocks from the VCO can feed to the DPA circuitry.



For more information on the fast PLL, see the *PLLs in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook*.

The eight phase-shifted clocks from the fast PLL feed to the DPA block. The DPA block selects the closest phase to the center of the serial data eye to sample the incoming data. This allows the source-synchronous circuitry to capture incoming data correctly regardless of the channel-to-channel or clock-to-channel skew. The DPA block locks to a phase closest to the serial data phase. The phase-aligned DPA clock is used to write the data into the synchronizer.

The synchronizer sits between the DPA block and the data realignment and SERDES circuitry. Since every channel utilizing the DPA block can have a different phase selected to sample the data, the synchronizer is needed to synchronize the data to the high-speed clock domain of the data realignment and the SERDES circuitry.

Document Revision History

Table 2–27 shows the revision history for this chapter.

Table 2–27. Document Revision History (Part 1 of 2)

Date and Document Version	Changes Made	Summary of Changes
May 2007, v4.3	Updated “Clock Control Block” section.	—
	Updated note in the “Clock Control Block” section.	—
	Deleted Tables 2-11 and 2-12.	—
	Updated notes to: <ul style="list-style-type: none"> • Figure 2–41 • Figure 2–42 • Figure 2–43 • Figure 2–45 	—
	Updated notes to Table 2–18.	—
	Moved Document Revision History to end of the chapter.	—
August 2006, v4.2	Updated Table 2–18 with note.	—
April 2006, v4.1	<ul style="list-style-type: none"> • Updated Table 2–13. • Removed Note 2 from Table 2–16. • Updated “On-Chip Termination” section and Table 2–19 to include parallel termination with calibration information. • Added new “On-Chip Parallel Termination with Calibration” section. • Updated Figure 2–44. 	<ul style="list-style-type: none"> • Added parallel on-chip termination description and specification. • Changed RCLK names to match the Quartus II software in Table 2–13.
December 2005, v4.0	Updated “Clock Control Block” section.	—
July 2005, v3.1	<ul style="list-style-type: none"> • Updated HyperTransport technology information in Table 2–18. • Updated HyperTransport technology information in Figure 2–57. • Added information on the asynchronous clear signal. 	—
May 2005, v3.0	<ul style="list-style-type: none"> • Updated “Functional Description” section. • Updated Table 2–3. • Updated “Clock Control Block” section. • Updated Tables 2–17 through 2–19. • Updated Tables 2–20 through 2–22. • Updated Figure 2–57. 	—
March 2005, 2.1	<ul style="list-style-type: none"> • Updated “Functional Description” section. • Updated Table 2–3. 	—

you need to support configuration input voltages of 1.8 V/1.5 V, you should set the VCCSEL to a logic high and the V_{CCIO} of the bank that contains the configuration inputs to 1.8 V/1.5 V.



For more information on multi-volt support, including information on using TDO and nCEO in multi-volt systems, refer to the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Configuration Schemes

You can load the configuration data for a Stratix II device with one of five configuration schemes (see Table 3–5), chosen on the basis of the target application. You can use a configuration device, intelligent controller, or the JTAG port to configure a Stratix II device. A configuration device can automatically configure a Stratix II device at system power-up.

You can configure multiple Stratix II devices in any of the five configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Stratix II FPGAs offer the following:

- Configuration data decompression to reduce configuration file storage
- Design security using configuration data encryption to protect your designs
- Remote system upgrades for remotely updating your Stratix II designs

Table 3–5 summarizes which configuration features can be used in each configuration scheme.

Table 3–5. Stratix II Configuration Features (Part 1 of 2)

Configuration Scheme	Configuration Method	Design Security	Decompression	Remote System Upgrade
FPP	MAX II device or microprocessor and flash device	✓ (1)	✓ (1)	✓
	Enhanced configuration device		✓ (2)	✓
AS	Serial configuration device	✓	✓	✓ (3)
PS	MAX II device or microprocessor and flash device	✓	✓	✓
	Enhanced configuration device	✓	✓	✓
	Download cable (4)	✓	✓	

Table 5–30. Series On-Chip Termination Specification for Top & Bottom I/O Banks (Part 2 of 2)

Notes (1), 2

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
50-Ω R _S 3.3/2.5	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 3.3/2.5 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 3.3/2.5 V	±30	±30	%
50-Ω R _T 2.5	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±30	±30	%
25-Ω R _S 1.8	Internal series termination with calibration (25-Ω setting)	V _{CCIO} = 1.8 V	±5	±10	%
	Internal series termination without calibration (25-Ω setting)	V _{CCIO} = 1.8 V	±30	±30	%
50-Ω R _S 1.8	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±30	±30	%
50-Ω R _T 1.8	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.8 V	±10	±15	%
50-Ω R _S 1.5	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±8	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±36	±36	%
50-Ω R _T 1.5	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.5 V	±10	±15	%
50-Ω R _S 1.2	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 1.2 V	±8	±10	%
	Internal series termination without calibration (50-Ω setting)	V _{CCIO} = 1.2 V	±50	±50	%
50-Ω R _T 1.2	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 1.2 V	±10	±15	%

Notes for Table 5–30:

- (1) The resistance tolerances for calibrated SOCT and POCT are for the moment of calibration. If the temperature or voltage changes over time, the tolerance may also change.
- (2) On-chip parallel termination with calibration is only supported for input pins.

Table 5–42. M-RAM Block Internal Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{MEGARC}	Synchronous read cycle time	1,866	2,774	1,866	2,911	1,777 1,866	3,189	1,777 1,866	3,716	ps
$t_{\text{MEGAWERESU}}$	Write or read enable setup time before clock	144		151		165 165		192		ps
$t_{\text{MEGAWEREH}}$	Write or read enable hold time after clock	39		40		44 44		52		ps
t_{MEGABESU}	Byte enable setup time before clock	50		52		57 57		67		ps
t_{MEGABEH}	Byte enable hold time after clock	39		40		44 44		52		ps
$t_{\text{MEGADATAASU}}$	A port data setup time before clock	50		52		57 57		67		ps
$t_{\text{MEGADATAAH}}$	A port data hold time after clock	243		255		279 279		325		ps
$t_{\text{MEGAADDRASU}}$	A port address setup time before clock	589		618		677 677		789		ps
$t_{\text{MEGAADDRAH}}$	A port address hold time after clock	241		253		277 277		322		ps
$t_{\text{MEGADATABSU}}$	B port setup time before clock	50		52		57 57		67		ps
$t_{\text{MEGADATABH}}$	B port hold time after clock	243		255		279 279		325		ps
$t_{\text{MEGAADDRBSU}}$	B port address setup time before clock	589		618		677 677		789		ps
$t_{\text{MEGAADDRBH}}$	B port address hold time after clock	241		253		277 277		322		ps
$t_{\text{MEGADATACO1}}$	Clock-to-output delay when using output registers	480	715	480	749	457 480	821	480	957	ps
$t_{\text{MEGADATACO2}}$	Clock-to-output delay without output registers	1,950	2,899	1,950	3,042	1,857 1,950	3,332	1,950	3,884	ps
t_{MEGACLKL}	Minimum clock low time	1,250		1,312		1,437 1,437		1,675		ps

Table 5–62. EP2S130 Row Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.680	1.760	3.070	3.351	3.892	ns
t_{COUT}	1.685	1.765	3.066	3.347	3.887	ns
t_{PLLCIN}	-0.113	-0.124	-0.12	-0.138	-0.168	ns
$t_{PLLCOUT}$	-0.108	-0.119	-0.124	-0.142	-0.173	ns

Table 5–63. EP2S130 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.690	1.770	3.075	3.362	3.905	ns
t_{COUT}	1.695	1.775	3.071	3.358	3.900	ns
t_{PLLCIN}	-0.087	-0.097	-0.075	-0.089	-0.11	ns
$t_{PLLCOUT}$	-0.082	-0.092	-0.079	-0.093	-0.115	ns

EP2S180 Clock Timing Parameters

Tables 5–64 through 5–67 show the maximum clock timing parameters for EP2S180 devices.

Table 5–64. EP2S180 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	2.001	2.095	3.643	3.984	4.634	ns
t_{COUT}	1.844	1.930	3.389	3.706	4.310	ns
t_{PLLCIN}	-0.307	-0.297	0.053	0.046	0.048	ns
$t_{PLLCOUT}$	-0.464	-0.462	-0.201	-0.232	-0.276	ns

Table 5–70. Stratix II IOE Programmable Delay on Row Pins *Note (1)*

Parameter	Paths Affected	Available Settings	Minimum Timing (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade	
			Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)	Min Offset (ps)	Max Offset (ps)
Input delay from pin to internal cells	Pad to I/O dataout to logic array	8	0 0	1,697 1,782	0 0	2,876 3,020	0	3,308	0	3,853
Input delay from pin to input register	Pad to I/O input register	64	0 0	1,956 2,054	0 0	3,270 3,434	0	3,761	0	4,381
Delay from output register to output pin	I/O output register to pad	2	0 0	316 332	0 0	525 525	0	575	0	670
Output enable pin delay	t_{xz} , t_{zx}	2	0 0	305 320	0 0	507 507	0	556	0	647

Notes to Table 5–70:

- (1) The incremental values for the settings are generally linear. For the exact delay associated with each setting, use the latest version of the Quartus II software.
- (2) The first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.
- (3) The first number applies to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices. The second number applies to -3 speed grade EP2S130 and EP2S180 devices.

Default Capacitive Loading of Different I/O Standards

See Table 5–71 for default capacitive loading of different I/O standards.

Table 5–71. Default Loading of Different I/O Standards for Stratix II (Part 1 of 2)

I/O Standard	Capacitive Load	Unit
LVTTTL	0	pF
LVC MOS	0	pF
2.5 V	0	pF
1.8 V	0	pF
1.5 V	0	pF
PCI	10	pF
PCI-X	10	pF
SSTL-2 Class I	0	pF

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 3 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
SSTL-18 Class I	4 mA	458	570	570	458	570	570	505	570	570
	6 mA	305	380	380	305	380	380	336	380	380
	8 mA	225	282	282	225	282	282	248	282	282
	10 mA	167	220	220	167	220	220	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
SSTL-18 Class II	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
1.8-V HSTL Class I	4 mA	245	282	282	245	282	282	229	282	282
	6 mA	164	188	188	164	188	188	153	188	188
	8 mA	123	140	140	123	140	140	114	140	140
	10 mA	110	124	124	110	124	124	108	124	124
	12 mA	97	110	110	97	110	110	104	110	110
1.8-V HSTL Class II	16 mA	101	104	104	-	-	-	99	104	104
	18 mA	98	102	102	-	-	-	93	102	102
	20 mA	93	99	99	-	-	-	88	99	99
1.5-V HSTL Class I	4 mA	168	196	196	168	196	196	188	196	196
	6 mA	112	131	131	112	131	131	125	131	131
	8 mA	84	99	99	84	99	99	95	99	99
	10 mA	87	98	98	-	-	-	90	98	98
	12 mA	86	98	98	-	-	-	87	98	98
1.5-V HSTL Class II	16 mA	95	101	101	-	-	-	96	101	101
	18 mA	95	100	100	-	-	-	101	100	100
	20 mA	94	101	101	-	-	-	104	101	101
Differential SSTL-2 Class II (3)	8 mA	364	680	680	-	-	-	350	680	680
	12 mA	163	207	207	-	-	-	188	207	207
	16 mA	118	147	147	-	-	-	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116

Table 5–102 shows the JTAG timing parameters and values for Stratix II devices.

Table 5–102. Stratix II JTAG Timing Parameters & Values				
Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	30		ns
t_{JCH}	TCK clock high time	13		ns
t_{JCL}	TCK clock low time	13		ns
t_{JPSU}	JTAG port setup time	3		ns
t_{JPH}	JTAG port hold time	5		ns
t_{JPCO}	JTAG port clock to output		11 (1)	ns
t_{JPZX}	JTAG port high impedance to valid output		14 (1)	ns
t_{JPXZ}	JTAG port valid output to high impedance		14 (1)	ns

Note to Table 5–102:

- (1) A 1 ns adder is required for each V_{CCIO} voltage step down from 3.3 V. For example, $t_{JPCO} = 12$ ns if V_{CCIO} of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.

Document Revision History

Table 5–103 shows the revision history for this chapter.

Table 5–103. Document Revision History (Part 1 of 3)		
Date and Document Version	Changes Made	Summary of Changes
April 2011, v4.5	Updated Table 5–3.	Added operating junction temperature for military use.
July 2009, v4.4	Updated Table 5–92.	Updated the spread spectrum modulation frequency (f_{SS}) from (100 kHz–500 kHz) to (30 kHz–150 kHz).
May 2007, v4.3	<ul style="list-style-type: none"> Updated R_{CONF} in Table 5–4. Updated f_{IN} (min) in Table 5–92. Updated f_{IN} and f_{INPFD} in Table 5–93. 	—
	Moved the Document Revision History section to the end of the chapter.	—